

Notice of References Cited	Application/Control No. 10/775,684	Applicant(s)/Patent Under Reexamination IWA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0103203 A1	06-2003	Isozaki et al.	356/237.2
	B	US-6,556,290 B	04-2003	Maeda et al.	356/237.2
	C	US-6,204,918 B1	03-2001	Isozaki et al.	356/239.8
	D	US-6,104,481 A	08-2000	Sekine et al.	356/237.5
	E	US-6,043,932 A	03-2000	Kusunose, Haruhiko	359/368
	F	US-6,104,945 A	08-2000	Modell et al.	600/473
	G	US-5,889,593 A	03-1999	Bareket, Noah	356/445
	H	US-5,179,422 A	01-1993	Peterson, Lauren M.	356/237.1
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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